**Product data sheet** 

## 1. General description

Planar passivated high commutation three quadrant triac in a TO263 (D²PAK) surface mountable plastic package intended for use in circuits where high static and dynamic dV/dt and high dl<sub>T</sub>/dt can occur. This triac will commutate the full RMS current at the maximum rated junction temperature ( $T_{j(max)}$  = 150 °C) without the aid of a snubber. It is used in applications where high junction operating temperature capability is required.

### 2. Features and benefits

- · 3Q technology for improved noise immunity
- · High commutation capability with maximum false trigger immunity
- High junction operating temperature capability (T<sub>i(max)</sub> = 150 °C)
- High voltage capability
- · High current capability
- · Less sensitive gate for highest noise immunity
- · Triggering in three quadrants only
- Very high immunity to false turn-on by dV/dt and fast transients
- · Surface mountable plastic package
- · Package is RoHS compliant

## 3. Applications

- Heating controls
- · High power motor control
- · High power switching
- Applications subject to high temperature (T<sub>i(max)</sub> = 150 °C)

### 4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
$V_{DRM}$	repetitive peak off-state voltage			-	-	800	V
I <sub>T(RMS)</sub>	RMS on-state current full sine wave; T <sub>mb</sub> ≤ 120 °C; Fig. 1; Fig. 2; Fig. 3			-	-	30	Α
I <sub>TSM</sub>	non-repetitive peak on- state current	full sine wave; $T_{j(init)}$ = 25 °C; $t_p$ = 20 ms; Fig. 4; Fig. 5		-	-	270	Α
		full sine wave; $T_{j(init)} = 25 \text{ °C}$ ; $t_p = 16.7 \text{ ms}$		-	-	297	Α
T <sub>j</sub>	junction temperature			-	-	150	°C
Static ch	Static characteristics						
I <sub>GT</sub>	gate trigger current	$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2+ \text{ G+;} $ $T_j = 25 \text{ °C; } \underline{\text{Fig. 7}}$		-	-	50	mA

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
		$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2+ \text{ G-};$ $T_j = 25 \text{ °C}; Fig. 7$	-	-	50	mA
		$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2- \text{G-};$ $T_j = 25 \text{ °C}; \frac{\text{Fig. 7}}{}$	-	-	50	mA
I <sub>H</sub>	holding current	V <sub>D</sub> = 12 V; T <sub>j</sub> = 25 °C; <u>Fig. 9</u>	-	-	75	mA
V <sub>T</sub>	on-state voltage	$I_T = 42 \text{ A}; T_j = 25 \text{ °C}; Fig. 10$	-	1.2	1.5	V
Dynamic	characteristics					
dV <sub>D</sub> /dt	rate of rise of off-state voltage	$V_{DM}$ = 536 V; $T_j$ = 125 °C; ( $V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform; gate open circuit	4000	-	-	V/µs
		$V_{DM}$ = 536 V; $T_j$ = 150 °C; ( $V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform; gate open circuit	2000	-	-	V/µs
dl <sub>com</sub> /dt	rate of change of commutating current	$V_D = 400 \text{ V}; T_j = 125 \text{ °C}; I_{T(RMS)} = 30 \text{ A};$ $dV_{com}/dt = 20 \text{ V/}\mu\text{s}; (snubberless condition); gate open circuit$	20	-	-	A/ms
		V <sub>D</sub> = 400 V; T <sub>j</sub> = 150 °C; I <sub>T(RMS)</sub> = 30 A; dV <sub>com</sub> /dt = 20 V/μs; (snubberless condition); gate open circuit	15	-	-	A/ms

# 5. Pinning information

### Table 2. Pinning information

Table 2.1 mining information								
Pin	Symbol	Description	Simplified outline	Graphic symbol				
1	T1	main terminal 1		<b>N</b> 1				
2	T2	main terminal 2		T2—T1				
3	G	gate		sym051				
mb	T2	mounting base; main terminal 2						

# 6. Ordering information

#### **Table 3. Ordering information**

•						
Type number	Package	Orderable part number	Packing	Small packing	Package	Package
	Name		method	quantity	version	issue date
BTA330B-800BT	TO263	BTA330B-800BTJ	Reel	800	TO263E	26-May-2017

# 7. Marking

#### Table 4. Marking codes

- table in manning details					
	Type number	Marking codes			
	BTA330B-800BT	BTA330B-800BT			

# 8. Limiting values

#### Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{DRM}$	repetitive peak off-state voltage		-	800	V
I <sub>T(RMS)</sub>	RMS on-state current full sine wave; T <sub>mb</sub> ≤ 120 °C; Fig. 1; Fig. 2; Fig. 3		-	30	А
I <sub>TSM</sub>	non-repetitive peak on- state current	full sine wave; T <sub>j(init)</sub> = 25 °C; t <sub>p</sub> = 20 ms; Fig. 4; Fig. 5	-	270	А
		full sine wave; $T_{j(init)} = 25 \text{ °C}$ ; $t_p = 16.7 \text{ ms}$	-	297	А
l <sup>2</sup> t	I <sup>2</sup> t for fusing	t <sub>P</sub> = 10 ms; sine wave pulse	-	364.5	A <sup>2</sup> s
dl <sub>⊤</sub> /dt	rate of rise of on-state current	I <sub>G</sub> = 100 mA	-	100	A/µs
I <sub>GM</sub>	peak gate current		-	2	А
$P_GM$	peak gate power		-	5	W
$P_{\text{G(AV)}}$	average gate power	over any 20 ms period	-	0.5	W
T <sub>stg</sub>	storage temperature		-40	150	°C
T <sub>j</sub>	junction temperature		-	150	°C

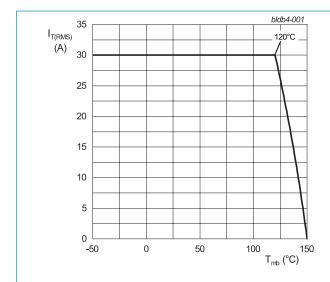
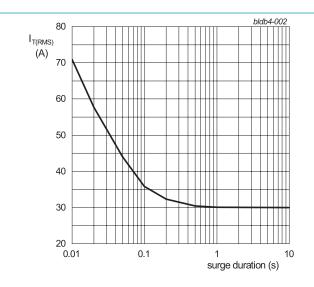
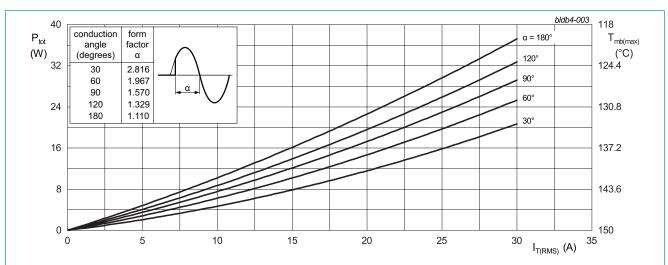


Fig. 1. RMS on-state current as a function of mounting base temperature; maximum values



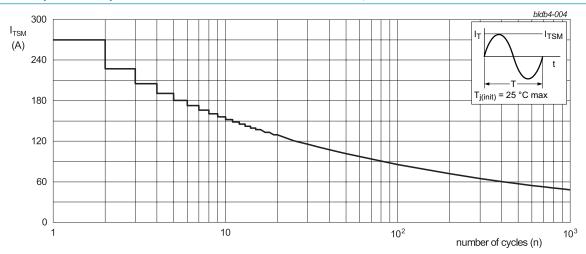
f = 50 Hz; T<sub>mb</sub> = 120 °C Fig. 2. RMS on-state current as a function of surge duration; maximum values



 $\alpha$  = conduction angle

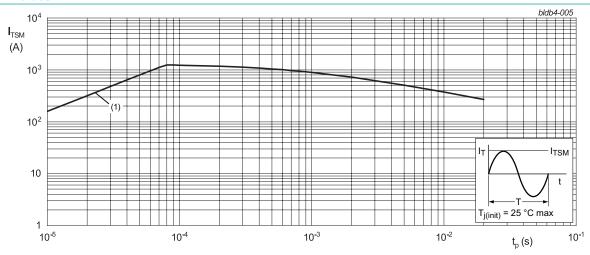
 $a = form factor = I_{T(RMS)} / I_{T(AV)}$ 

Fig. 3. Total power dissipation as a function of RMS on-state current; maximum values



f = 50 Hz

Fig. 4. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values



t<sub>0</sub> ≤ 20 ms

(1) dl<sub>T</sub>/dt limit

Fig. 5. Non-repetitive peak on-state current as a function of pulse duration; maximum values

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### 9. Thermal characteristics

**Table 6. Thermal characteristics** 

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R <sub>th(j-mb)</sub>	thermal resistance from junction to mounting base	full cycle; Fig 6	-	-	0.8	K/W
$R_{\text{th(j-a)}}$	thermal resistance from junction to ambient	printed circuit board mounted; minimum footprint	-	55	-	K/W

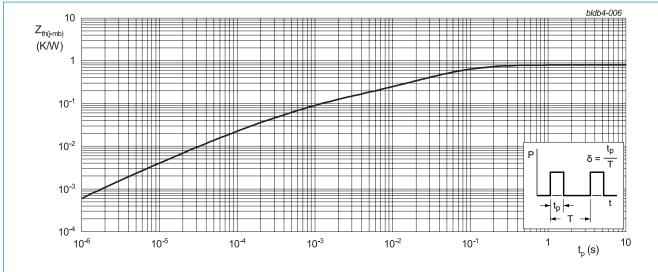
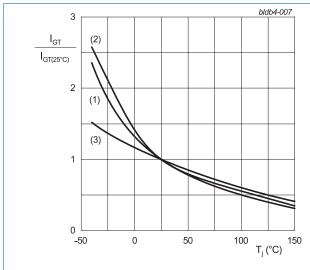


Fig. 6. Transient thermal impedance from junction to mounting base as a function of pulse duration

## 10. Characteristics

**Table 7. Characteristics** 

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static ch	aracteristics				·	
I <sub>GT</sub>	gate trigger current	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2+ G+;$ $T_j = 25 \text{ °C}; Fig. 7$	-	-	50	mA
		$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2+ \text{ G-};$ $T_j = 25 \text{ °C}; Fig. 7$	-	-	50	mA
		$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2- \text{ G-};$ $T_j = 25 \text{ °C}; Fig. 7$	-	-	50	mA
I <sub>L</sub>	latching current	$V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; T2+ G+;$ $T_j = 25 \text{ °C}; Fig. 8$	-	-	80	mA
		$V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; T2+ G-;$ $T_j = 25 \text{ °C}; Fig. 8$	-	-	100	mA
		$V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; \text{ T2- G-};$ $T_j = 25 \text{ °C}; \frac{\text{Fig. 8}}{\text{Fig. 8}}$	-	-	80	mA
I <sub>H</sub>	holding current	V <sub>D</sub> = 12 V; T <sub>j</sub> = 25 °C; <u>Fig. 9</u>	-	-	75	mA
$V_T$	on-state voltage	I <sub>τ</sub> = 42 A; T <sub>j</sub> = 25 °C; <u>Fig. 10</u>	-	1.2	1.5	V
V <sub>GT</sub> gate trigger vo	gate trigger voltage	$V_D = 12 \text{ V; } I_T = 0.1 \text{ A;} T_j = 25 \text{ °C; } Fig. 11$	-	0.9	1.3	V
		V <sub>D</sub> = 400 V; I <sub>T</sub> = 0.1 A;T <sub>j</sub> = 150 °C	0.2	0.45	-	V
I <sub>D</sub>	off-state current	V <sub>D</sub> = 800 V; T <sub>j</sub> = 25 °C	-	-	10	μA
		V <sub>D</sub> = 800 V; T <sub>j</sub> = 125 °C	-	0.4	2	mA
Dynamic	characteristics					
dV <sub>D</sub> /dt	rate of rise of off-state voltage	$V_{DM}$ = 536 V; $T_j$ = 125 °C; ( $V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform; gate open circuit	4000	-	-	V/µs
		$V_{DM}$ = 536 V; $T_j$ = 150 °C; $(V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform; gate open circuit	2000	-	-	V/µs
dI <sub>com</sub> /dt	rate of change of commutating current	$V_D = 400 \text{ V; } T_j = 125 \text{ °C; } I_{T(RMS)} = 30 \text{ A;}$ $dV_{com}/dt = 20 \text{ V/}\mu\text{s; (snubberless condition); gate open circuit}$	20	-	-	A/ms
		$V_D = 400 \text{ V}; T_j = 150 ^{\circ}\text{C}; I_{T(RMS)} = 30 \text{ A};$ $dV_{com}/dt = 20 \text{ V}/\mu\text{s}; (snubberless condition); gate open circuit$	15	-	-	A/ms



- (1) T2- G-
- (2) T2+ G-
- (3) T2+ G+

Fig. 7. Normalized gate trigger current as a function of junction temperature

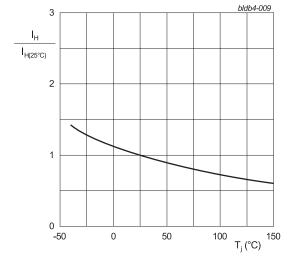


Fig. 9. Normalized holding current as a function of junction temperature

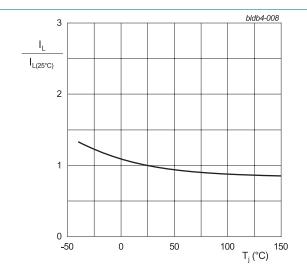
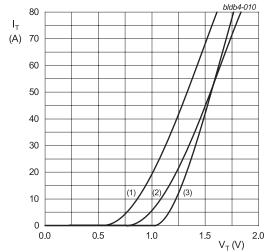


Fig. 8. Normalized latching current as a function of junction temperature



 $V_o = 1.011 \text{ V}; R_s = 0.0110 \Omega$ 

- (1)  $T_j$  = 150 °C; typical values (2)  $T_j$  = 150 °C; maximum values
- (3)  $T_i = 25$  °C; maximum values

Fig. 10. On-state current as a function of on-state voltage

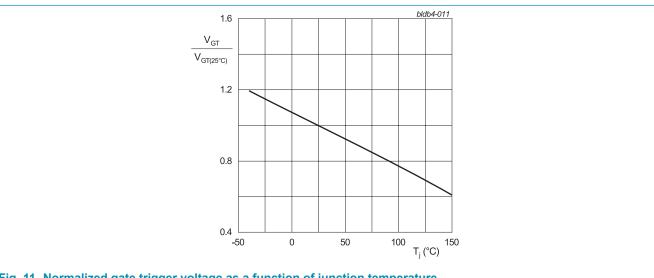
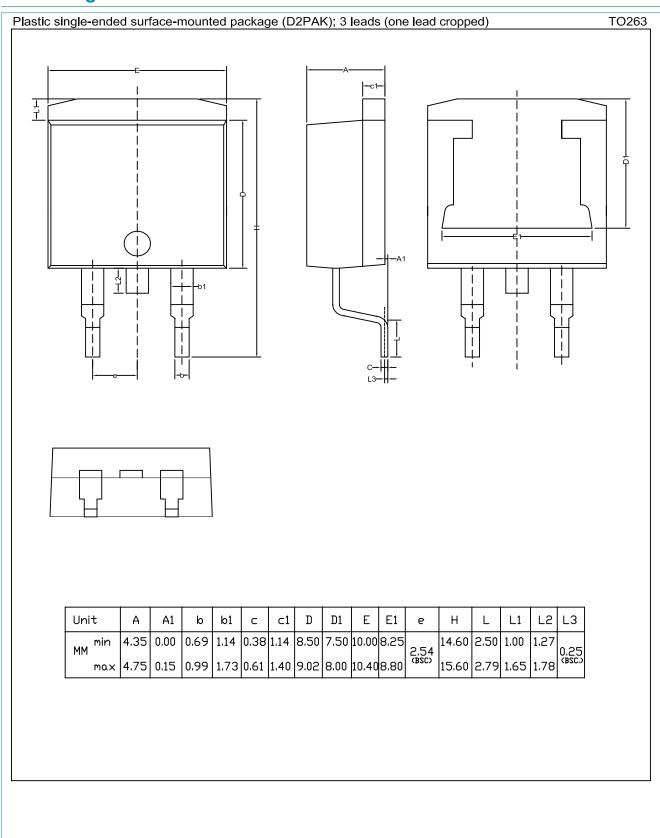


Fig. 11. Normalized gate trigger voltage as a function of junction temperature

# 11. Package outline



### 12. Legal information

#### Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
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